

Notic o f Reference s Cited

Application/Control No.

09/945,535

Applicant(s)/Patent Under

Reexamination

AHN ET AL.

Examiner

David S Blum

Art Unit

2813

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-US006211035B1	04-2001	Moise et al	438/396
	B	US-4920071	04-1990	Thomas	438/585
	C	US-4647947	03-1987	Takeoka et al	346/135.1
	D	US-5,795,808	08-1998	Park	438/301
	E	US-4333808	06-1982	Bhattacharyya et al	204/192D
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Milton Ohring THE MATERIALS SCIENCE OF THIN FILMS Academic Press, Inc 1992 pages vi, 118, 121, 125
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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